Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/554,254	NAKAJIMA ET AL.	
Examiner	Art Unit	
Erich A. Leeser	1624	

SEARCHED				
Class	Subclass	Date	Examiner	
	,			
		•		
,		·		
			•	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
class/subcla	earch, for ass info., see e right	7/2/2007	EL

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
updated PALM inventor search	7/2/2007	EL
updated STN structure search	7/2/2007	EL
updated EAST 544/251, 544/252, 514/267, 540/560, 540/562, 540/469, 540/559 with search terms, see printout	7/2/2007	EL